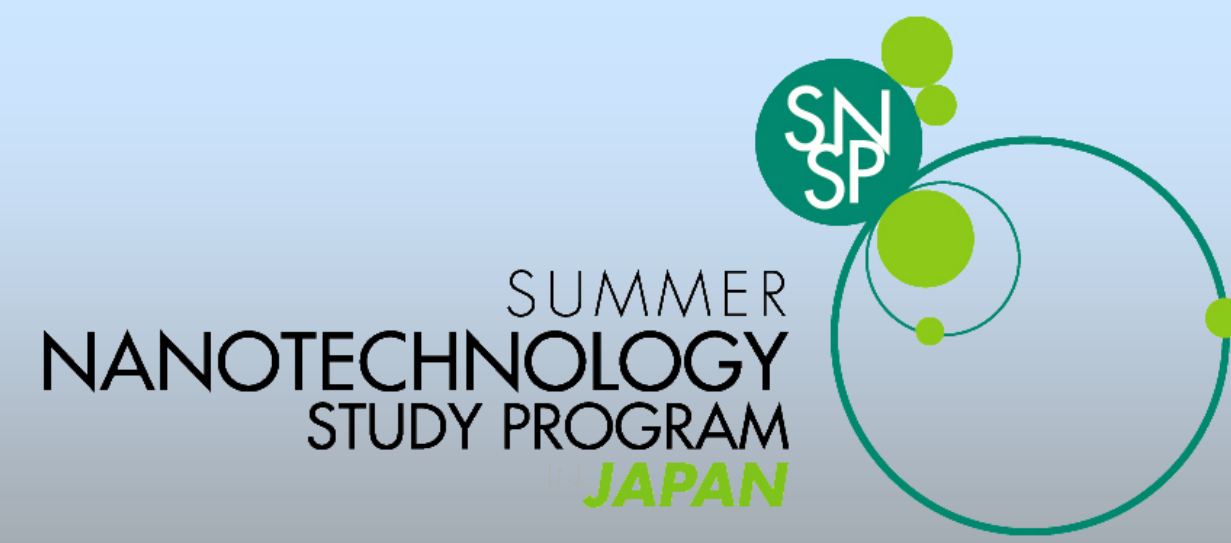


# The Study of Tip-Induced Deformations in Single-Walled Carbon Nanotubes Using Tip-Enhanced Near-Field Raman Spectroscopy

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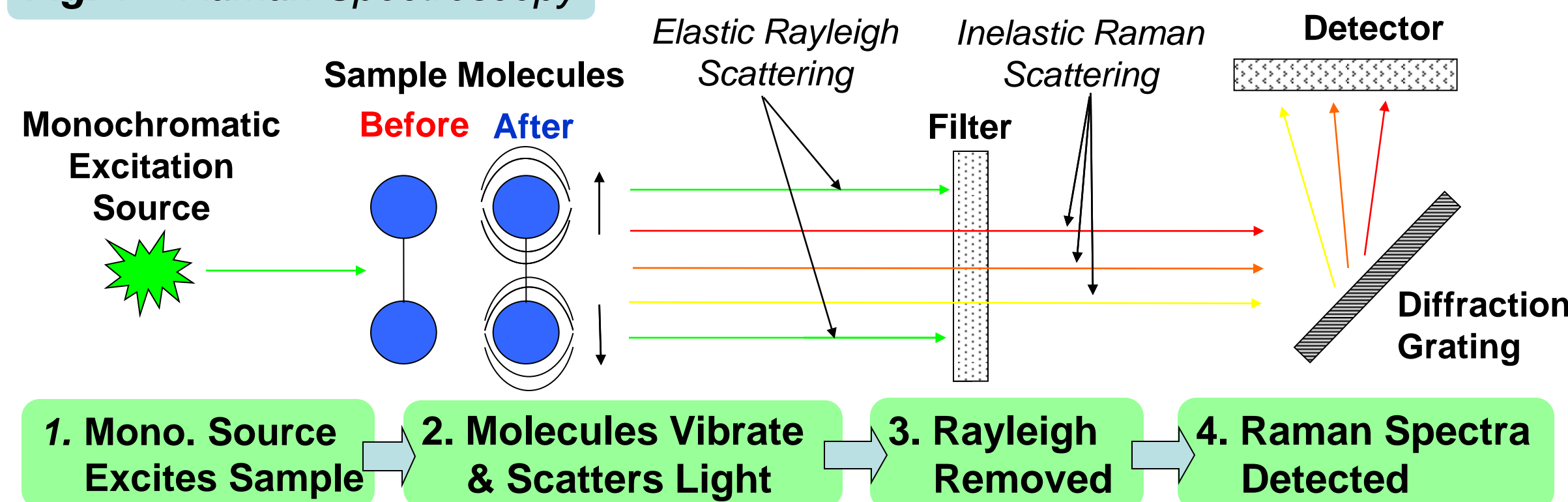
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## BACKGROUND

### Raman Spectroscopy

Fig. 1 – Raman Spectroscopy



### Carbon Nanotubes (CNT)

• Possess electronic and vibrational properties which are dependent on the CNTs' chirality (detected with Raman spectroscopy)

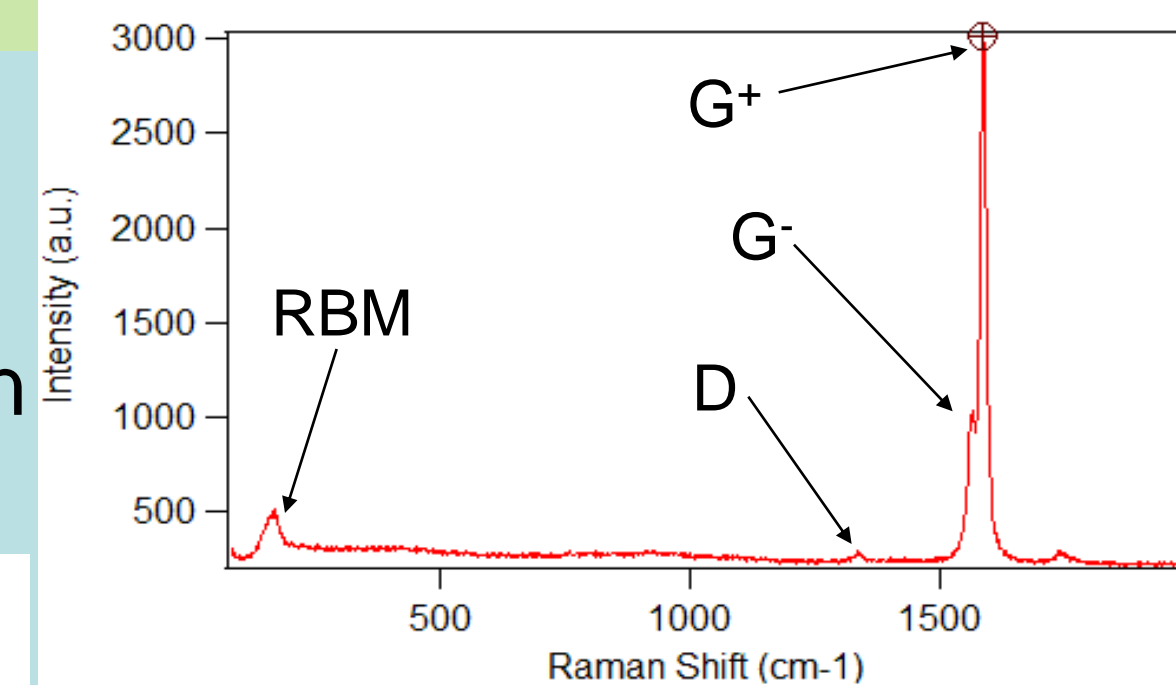


Fig. 2 – Raman Spectrum of CNT

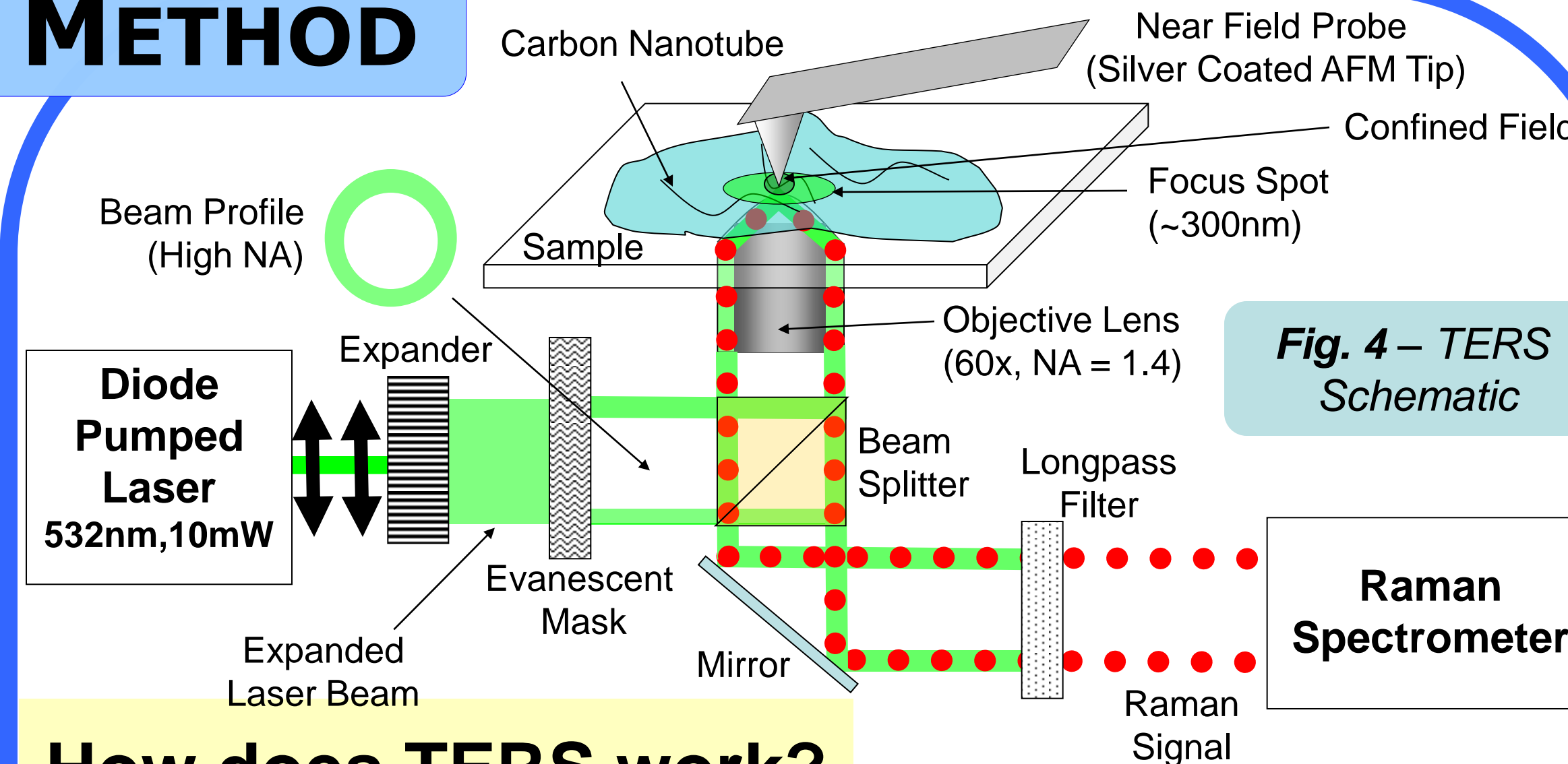
• Deformations alter the CNTs' energy band structure thereby altering their characteristics

• Shifts in the phonon modes result from these alterations

### Significance

- **Far-field Raman Spectroscopy** has **low spatial resolution** ~300nm – (due to diffraction limit of propagating light  $d = \lambda/2$ )
- **Tip-Enhanced Raman Spectroscopy (TERS)** can achieve a spatial resolution of less than 30nm
- **Raman Scattering** is **very weak** compared to **Rayleigh Sct.** (~1 in 10 million photons in a scattering event are Raman!)
- **Manipulation of CNTs** could cause **loss in Raman intensity**
- **TERS increases the Raman Scattering response by a factor of  $10^0 - 10^4$**

## METHOD

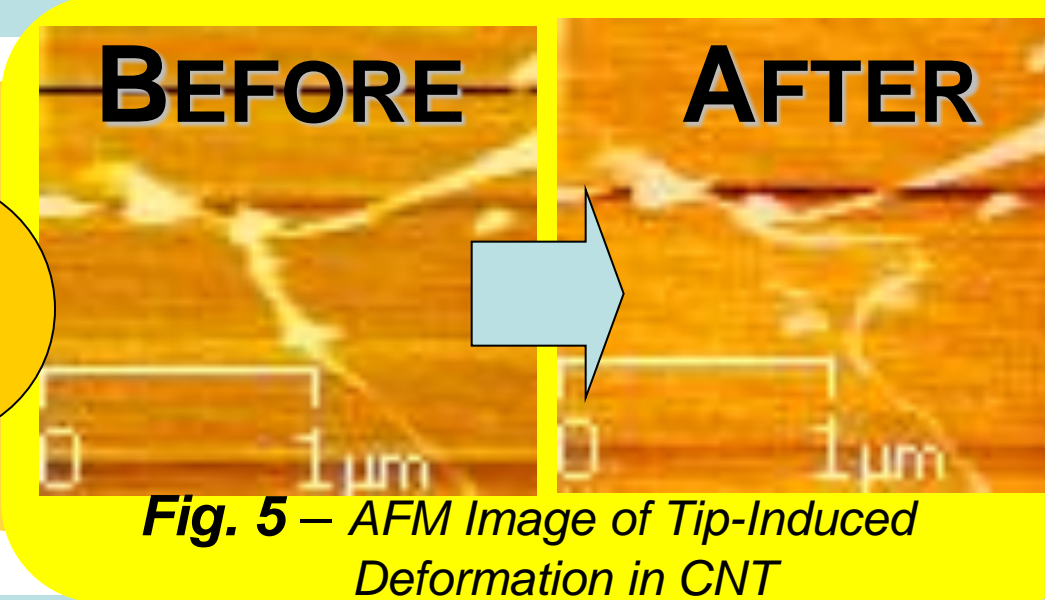


### How does TERS work?

- **Evanescent illumination** decreases the spot size of the laser confining the illuminated region of the sample
- **High NA p-polarized component** of the laser increases the electromagnetic field along the metallized tip
- Propagating photons are captured and confined at the apex of the hovering conical **silver coated silicon tip** due to coupling with localized **surface plasmon polaritons**

### Process

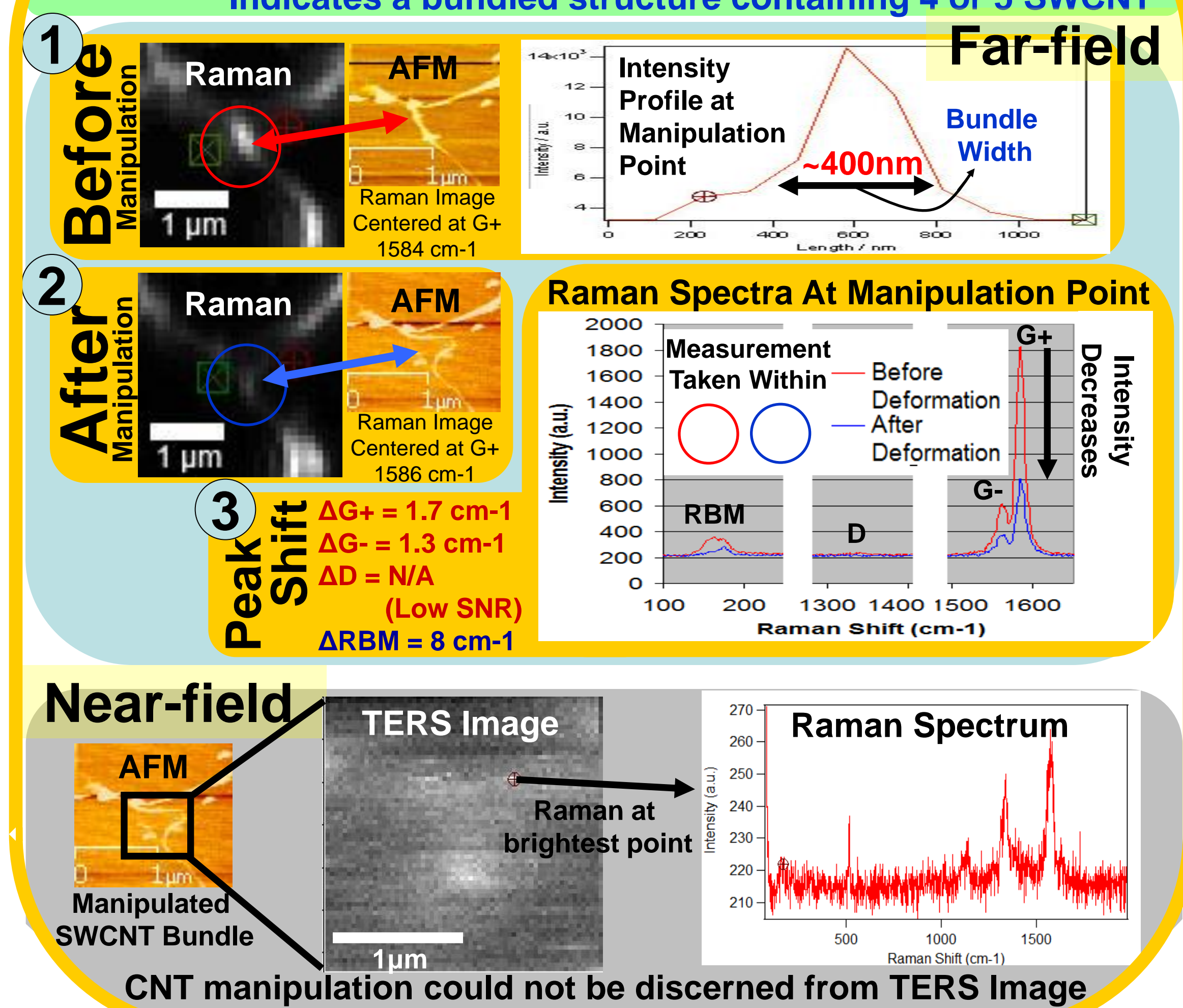
1. Spincoated and then baked CoMoCAT SWCNT onto glass slides
2. Used an **AFM-Raman System** comprised of a SII AFM system and Nikon Optical Microscope
3. **Far-field image** of the SWCNT was taken by raster scanning the sample with the setup in Fig. 4 but **with the tip and evanescent mask removed**
4. Using a silicon **Dynamic Force Microscopy (DFM)** tip, a **~430 nm horizontal defect** was introduced



**Far-field** (as in step 2) and **near-field** (using the setup of Fig. 4 with the tip constantly over the focal point) images of the manipulated SWCNT were taken

## RESULTS

Manipulation region was about **5 nm wide** - determined with DFM  
Indicates a bundled structure containing **4 or 5 SWCNT**



## CONCLUSION

- TERS was **not supported** by results, but it still exists
- Proved the **necessity of TERS** because:
  1. ~5nm bundle was measured ~400nm using Far-field
  2. D-band was **indiscernible from noise** after defect
- **RBM peak shift** could indicate a shift in the orientation of the bundled CNTs or change in CNT band structure

### Future Work

- Work with a single CNT strand instead of bundle
- Obtain data showcasing TERS enhancement
- Develop new opto-electric devices using the SWCNT structural deformation relation to electronic structure

### Acknowledgements

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